



Welcome to [E-XFL.COM](https://www.e-xfl.com)

Understanding [Embedded - FPGAs \(Field Programmable Gate Array\)](#)

Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

Applications of Embedded - FPGAs

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications.

Details

Product Status	Obsolete
Number of LABs/CLBs	-
Number of Logic Elements/Cells	-
Total RAM Bits	-
Number of I/O	83
Number of Gates	24000
Voltage - Supply	3V ~ 3.6V, 4.75V ~ 5.25V
Mounting Type	Surface Mount
Operating Temperature	0°C ~ 70°C (TA)
Package / Case	100-BQFP
Supplier Device Package	100-PQFP (20x14)
Purchase URL	https://www.e-xfl.com/product-detail/microchip-technology/a42mx16-fpq100

Figures

Figure 1	Ordering Information	3
Figure 2	42MX C-Module Implementation	7
Figure 3	42MX C-Module Implementation	7
Figure 4	42MX S-Module Implementation	8
Figure 5	A42MX24 and A42MX36 D-Module Implementation	9
Figure 6	A42MX36 Dual-Port SRAM Block	9
Figure 7	MX Routing Structure	10
Figure 8	Clock Networks of 42MX Devices	11
Figure 9	Quadrant Clock Network of A42MX36 Devices	11
Figure 10	42MX I/O Module	12
Figure 11	PCI Output Structure of A42MX24 and A42MX36 Devices	12
Figure 12	Silicon Explorer II Setup with 40MX	16
Figure 13	Silicon Explorer II Setup with 42MX	17
Figure 14	42MX IEEE 1149.1 Boundary Scan Circuitry	18
Figure 15	Device Selection Wizard	19
Figure 16	Typical Output Drive Characteristics (Based Upon Measured Data)	28
Figure 17	40MX Timing Model*	30
Figure 18	42MX Timing Model	30
Figure 19	42MX Timing Model (Logic Functions Using Quadrant Clocks)	31
Figure 20	42MX Timing Model (SRAM Functions)	32
Figure 21	Output Buffer Delays	32
Figure 22	AC Test Loads	33
Figure 23	Input Buffer Delays	33
Figure 24	Module Delays	33
Figure 25	Flip-Flops and Latches	34
Figure 26	Input Buffer Latches	34
Figure 27	Output Buffer Latches	35
Figure 28	Decode Module Timing	35
Figure 29	SRAM Timing Characteristics	35
Figure 30	42MX SRAM Write Operation	36
Figure 31	42MX SRAM Synchronous Read Operation	36
Figure 32	42MX SRAM Asynchronous Read Operation—Type 1 (Read Address Controlled)	36
Figure 33	42MX SRAM Asynchronous Read Operation—Type 2 (Write Address Controlled)	37
Figure 34	42MX Junction Temperature and Voltage Derating Curves (Normalized to $T_J = 25^\circ\text{C}$, $V_{CCA} = 5.0\text{ V}$)	38
Figure 35	40MX Junction Temperature and Voltage Derating Curves (Normalized to $T_J = 25^\circ\text{C}$, $V_{CC} = 5.0\text{ V}$)	39
Figure 36	42MX Junction Temperature and Voltage Derating Curves (Normalized to $T_J = 25^\circ\text{C}$, $V_{CCA} = 3.3\text{ V}$)	39
Figure 37	40MX Junction Temperature and Voltage Derating Curves (Normalized to $T_J = 25^\circ\text{C}$, $V_{CC} = 3.3\text{ V}$)	40
Figure 38	PL44	86
Figure 39	PL68	88
Figure 40	PL84	90
Figure 41	PQ100	93
Figure 42	PQ144	97
Figure 43	PQ160	102
Figure 44	PQ208	107
Figure 45	PQ240	113
Figure 46	VQ80	120
Figure 47	VQ100	123
Figure 48	TQ176	126
Figure 49	CQ208	131
Figure 50	CQ256	138

1 Revision History

The revision history describes the changes that were implemented in the document. The changes are listed by revision, starting with the most current publication.

1.1 Revision 15.0

The following is a summary of the changes in revision 15.0 of this document.

- Table 15, page 21 is edited to add the footnote, $V_{IH}(\text{Min})$ is 2.4V for A42MX36 family. This applies only to VCCI of 5V and is not applicable to VCCI of 3.3V
- Table 22, page 25 is edited to add the footnote, $V_{IH}(\text{Min})$ is 2.4V for A42MX36 family. This applies only to VCCI of 5V and is not applicable to VCCI of 3.3V
- Table 23, page 25 is edited to add the footnote, $V_{IH}(\text{Min})$ is 2.4V for A42MX36 family. This applies only to VCCI of 5V and is not applicable to VCCI of 3.3V

1.2 Revision 14.0

The following is a summary of the changes in revision 14.0 of this document.

- Added CQFP package information for A42MX16 device in Product Profile, page 1 and Ceramic Device Resources, page 4 (SAR 79522).
- Added Military (M) and MIL-STD-883 Class B (B) grades for CPGA 132 Package and added Commercial (C), Military (M), and MIL-STD-883 Class B (B) grades for CQFP 172 Package in Temperature Grade Offerings, page 5 (SAR 79519)
- Changed Silicon Sculptor II to Silicon Sculptor in Programming, page 12 (SAR 38754)
- Added Figure 53, page 158 CQ172 package (SAR 79522).

1.3 Revision 13.0

The following is a summary of the changes in revision 13.0 of this document.

- Added Figure 42, page 97 PQ144 Package for A42MX09 device (SAR 69776)
- Added Figure 52, page 153 PQ132 Package for A42MX09 device (SAR 69776)

1.4 Revision 12.0

The following is a summary of the changes in revision 12.0 of this document.

- Added information on power-up behavior for A42MX24 and A42MX36 devices to the Power Supply, page 13 (SAR 42096)
- Corrected the inadvertent mistake in the naming of the PL68 pin assignment table (SARs 48999, 49793)

1.5 Revision 11.0

The following is a summary of the changes in revision 11.0 of this document.

- The FuseLock logo and accompanying text was removed from the User Security, page 12. This marking is no longer used on Microsemi devices (PCN 0915)
- The Development Tool Support, page 19 was updated (SAR 38512)

1.6 Revision 10.0

The following is a summary of the changes in revision 10.0 of this document.

- Ordering Information, page 3 was updated to include lead-free package ordering codes (SAR 21968)
- The User Security, page 12 was revised to clarify that although no existing security measures can give an absolute guarantee, Microsemi FPGAs implement the best security available in the industry (SAR 34673)

2.4 Plastic Device Resources

Table 2 • Plastic Device Resources

Device	User I/Os											
	PLCC 44-Pin	PLCC 68-Pin	PLCC 84-Pin	PQFP 100-Pin	PQFP 144-Pin	PQFP 160-Pin	PQFP 208-Pin	PQFP 240-Pin	VQFP 80-Pin	VQFP 100-Pin	TQFP 176-Pin	PBGA 272-Pin
A40MX02	34	57	—	57	—	—	—	—	57	—	—	—
A40MX04	34	57	69	69	—	—	—	—	69	—	—	—
A42MX09	—	—	72	83	95	101	—	—	—	83	104	—
A42MX16	—	—	72	83	—	125	140	—	—	83	140	—
A42MX24	—	—	72	—	—	125	176	—	—	—	150	—
A42MX36	—	—	—	—	—	—	176	202	—	—	—	202

Note: Package Definitions: PLCC = Plastic Leaded Chip Carrier, PQFP = Plastic Quad Flat Pack, TQFP = Thin Quad Flat Pack, VQFP = Very Thin Quad Flat Pack, PBGA = Plastic Ball Grid Array

2.5 Ceramic Device Resources

Table 3 • Ceramic Device Resources

Device	User I/Os			
	CPGA 132-Pin	CQFP 172-Pin	CQFP 208-Pin	CQFP 256-Pin
A42MX09	95			
A42MX16		131		
A42MX36			176	202

Note: Package Definitions: CQFP = Ceramic Quad Flat Pack

Each I/O cell has three boundary-scan register cells, each with a serial-in, serial-out, parallel-in, and parallel-out pin. The serial pins are used to serially connect all the boundary-scan register cells in a device into a boundary-scan register chain, which starts at the TDI pin and ends at the TDO pin. The parallel ports are connected to the internal core logic tile and the input, output and control ports of an I/O buffer to capture and load data into the register to control or observe the logic state of each I/O.

Figure 14 • 42MX IEEE 1149.1 Boundary Scan Circuitry

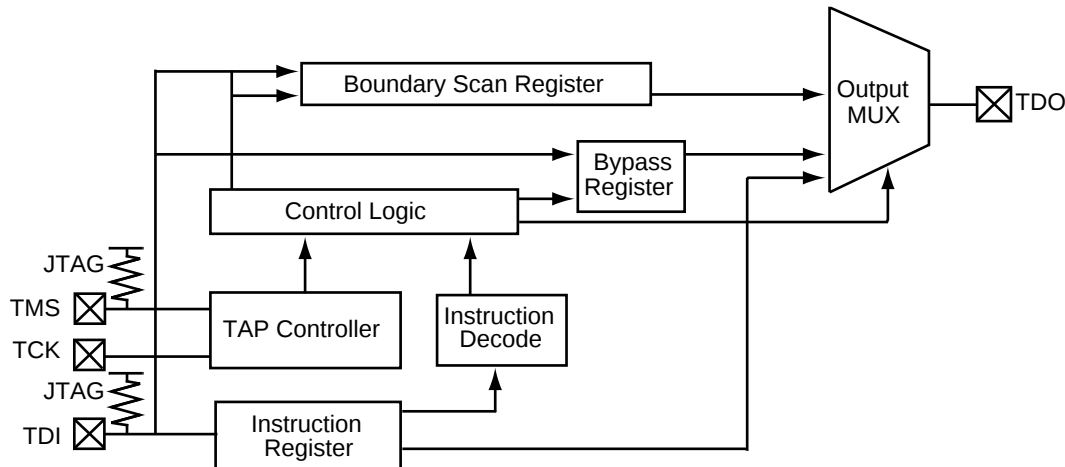


Table 9 • Test Access Port Descriptions

Port	Description
TMS (Test Mode Select)	Serial input for the test logic control bits. Data is captured on the rising edge of the test logic clock (TCK).
TCK (Test Clock Input)	Dedicated test logic clock used serially to shift test instruction, test data, and control inputs on the rising edge of the clock, and serially to shift the output data on the falling edge of the clock. The maximum clock frequency for TCK is 20 MHz.
TDI (Test Data Input)	Serial input for instruction and test data. Data is captured on the rising edge of the test logic clock.
TDO (Test Data Output)	Serial output for test instruction and data from the test logic. TDO is set to an Inactive Drive state (high impedance) when data scanning is not in progress.

Table 10 • Supported BST Public Instructions

Instruction	IR Code (IR2.IR0)	Instruction Type	Description
EXTEST	000	Mandatory	Allows the external circuitry and board-level interconnections to be tested by forcing a test pattern at the output pins and capturing test results at the input pins.
SAMPLE/PRELOAD	001	Mandatory	Allows a snapshot of the signals at the device pins to be captured and examined during operation
HIGH Z	101	Optional	Tristates all I/Os to allow external signals to drive pins. See the IEEE Standard 1149.1 specification.
CLAMP	110	Optional	Allows state of signals driven from component pins to be determined from the Boundary-Scan Register. See the IEEE Standard 1149.1 specification for details.
BYPASS	111	Mandatory	Enables the bypass register between the TDI and TDO pins. The test data passes through the selected device to adjacent devices in the test chain.

3.9.1 Mixed 5.0V/3.3V Electrical Specifications

Table 22 • Mixed 5.0V/3.3V Electrical Specifications

Symbol	Parameter	Commercial		Commercial –F		Industrial		Military		Units
		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
VOH ¹	IOH = –10 mA	2.4		2.4						V
	IOH = –4 mA					2.4		2.4		V
VOL ¹	IOL = 10 mA	0.5		0.5						V
	IOL = 6 mA					0.4		0.4		V
VIL		–0.3	0.8	–0.3	0.8	–0.3	0.8	–0.3	0.8	V
VIH ²		2.0	VCCA + 0.3	2.0	VCCA + 0.3	2.0	VCCA + 0.3	2.0	VCCA + 0.3	V
IL	VIN = 0.5 V	–10		–10		–10		–10		μA
IH	VIN = 2.7 V	–10		–10		–10		–10		μA
Input Transition Time, TR and TF		500		500		500		500		ns
C _{IO} I/O Capacitance		10		10		10		10		pF
Standby Current, ICC ³	A42MX09	5		25		25		25		mA
	A42MX16	6		25		25		25		mA
	A42MX24, A42MX36	20		25		25		25		mA
Low Power Mode Standby Current		0.5		ICC – 5.0		ICC – 5.0		ICC – 5.0		mA
I/O I/O source sink current Can be derived from the <i>IBIS model</i> (http://www.microsemi.com/soc/techdocs/models/ibis.html)										

1. Only one output tested at a time. VCCI = min.

2. VIH(Min) is 2.4V for A42MX36 family. This applies only to VCCI of 5V and is not applicable to VCCI of 3.3V

3. All outputs unloaded. All inputs = VCCI or GND

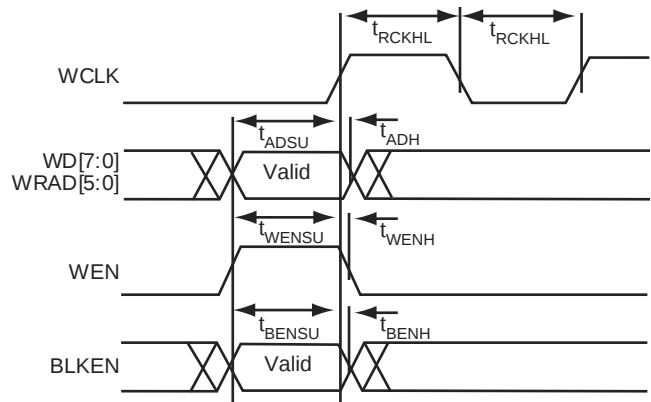
3.9.2 Output Drive Characteristics for 5.0 V PCI Signaling

MX PCI device I/O drivers were designed specifically for high-performance PCI systems. Figure 16, page 28 shows the typical output drive characteristics of the MX devices. MX output drivers are compliant with the PCI Local Bus Specification.

Table 23 • DC Specification (5.0 V PCI Signaling)¹

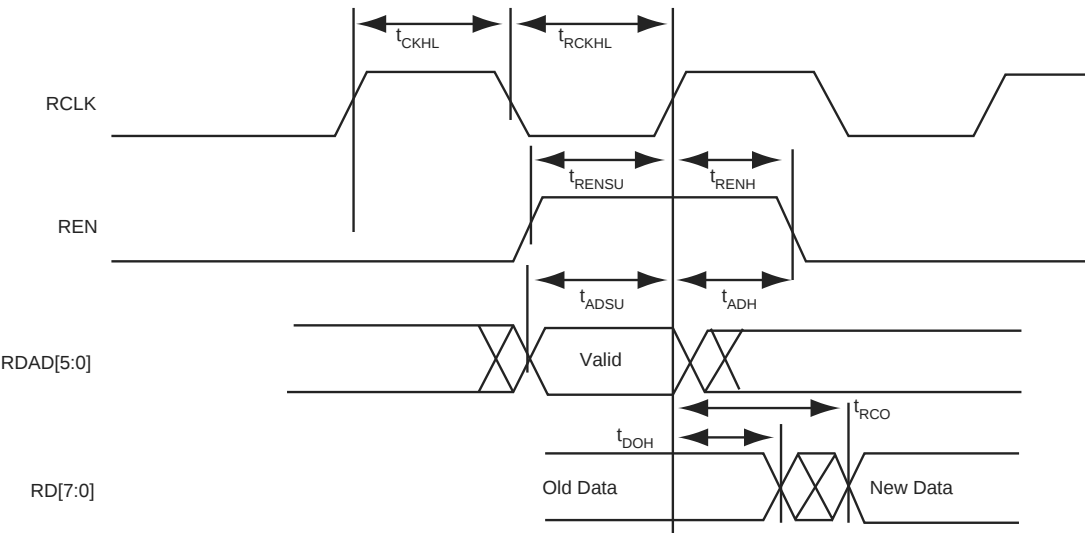
Symbol	Parameter	Condition	PCI		MX		Units
			Min.	Max.	Min.	Max.	
VCCI	Supply Voltage for I/Os		4.75	5.25	4.75	5.25 ²	V
VIH ³	Input High Voltage		2.0	VCC + 0.5	2.0	VCCI + 0.3	V
VIL	Input Low Voltage		–0.5	0.8	–0.3	0.8	V
IIH	Input High Leakage Current	VIN = 2.7 V		70	—	10	μA
IIL	Input Low Leakage Current	VIN=0.5 V		–70	—	–10	μA
VOH	Output High Voltage	IOUT = –2 mA IOUT = –6 mA	2.4		3.84		V
VOL	Output Low Voltage	IOUT = 3 mA, 6 mA		0.55	—	0.33	V

Figure 30 • 42MX SRAM Write Operation



Note: Identical timing for falling edge clock

Figure 31 • 42MX SRAM Synchronous Read Operation



Note: Identical timing for falling edge clock

Figure 32 • 42MX SRAM Asynchronous Read Operation—Type 1 (Read Address Controlled)

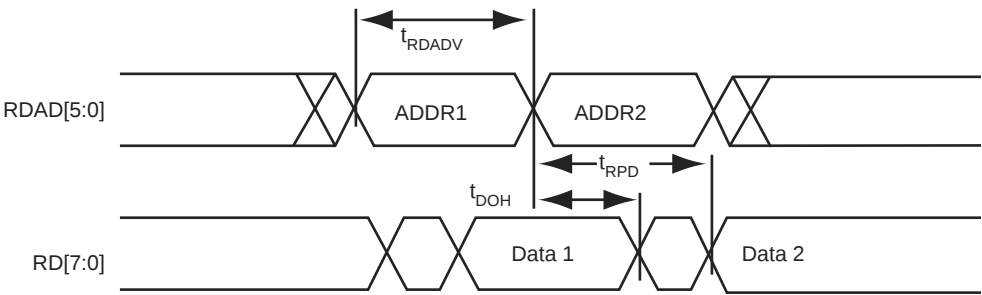


Table 37 • A40MX04 Timing Characteristics (Nominal 3.3 V Operation) (continued)(Worst-Case Commercial Conditions, VCC = 3.0 V, T_J = 70°C)

Parameter / Description		–3 Speed		–2 Speed		–1 Speed		Std Speed		–F Speed		Units
		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
t _{WCLKA}	Flip-Flop (Latch) Clock Active Pulse Width	4.6		5.3		5.6		7.0		9.8		ns
t _{WASYN}	Flip-Flop (Latch) Asynchronous Pulse Width	4.6		5.3		5.6		7.0		9.8		ns
t _A	Flip-Flop Clock Input Period	6.8		7.8		8.9		10.4		14.6		ns
f _{MAX}	Flip-Flop (Latch) Clock Frequency (FO = 128)		109		101		92		80		48	MHz
Input Module Propagation Delays												
t _{INYH}	Pad-to-Y HIGH		1.0		1.1		1.3		1.5		2.1	ns
t _{INYL}	Pad-to-Y LOW		0.9		1.0		1.1		1.3		1.9	ns

Table 37 • A40MX04 Timing Characteristics (Nominal 3.3 V Operation) (continued)(Worst-Case Commercial Conditions, VCC = 3.0 V, T_J = 70°C)

Parameter / Description		–3 Speed		–2 Speed		–1 Speed		Std Speed		–F Speed		Units
		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
CMOS Output Module Timing ⁴												
t _{DLH}	Data-to-Pad HIGH		5.5		6.4		7.2		8.5		11.9	ns
t _{DHL}	Data-to-Pad LOW		4.8		5.5		6.2		7.3		10.2	ns
t _{ENZH}	Enable Pad Z to HIGH		4.7		5.5		6.2		7.3		10.2	ns
t _{ENZL}	Enable Pad Z to LOW		6.8		7.9		8.9		10.5		14.7	ns
t _{ENHZ}	Enable Pad HIGH to Z		11.1		12.8		14.5		17.1		23.9	ns
t _{ENLZ}	Enable Pad LOW to Z		8.2		9.5		10.7		12.6		17.7	ns
d _{TLH}	Delta LOW to HIGH		0.05		0.05		0.06		0.07		0.10	ns/pF
d _{THL}	Delta HIGH to LOW		0.03		0.03		0.04		0.04		0.06	ns/pF

1. Routing delays are for typical designs across worst-case operating conditions. These parameters should be used for estimating device performance. Post-route timing analysis or simulation is required to determine actual performance.
2. Set-up times assume fanout of 3. Further testing information can be obtained from the Timer utility.
3. The hold time for the DFME1A macro may be greater than 0 ns. Use the Timer tool from the Designer software to check the hold time for this macro.
4. Delays based on 35 pF loading.

Table 38 • A42MX09 Timing Characteristics (Nominal 5.0 V Operation) (Worst-Case Commercial Conditions, VCCA = 4.75 V, T_J = 70°C)

Parameter / Description		–3 Speed		–2 Speed		–1 Speed		Std Speed		–F Speed		Units
		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
Logic Module Propagation Delays ¹												
t _{PD1}	Single Module		1.2		1.3		1.5		1.8		2.5	ns
t _{CO}	Sequential Clock-to-Q		1.3		1.4		1.6		1.9		2.7	ns
t _{GO}	Latch G-to-Q		1.2		1.4		1.6		1.8		2.6	ns
t _{RS}	Flip-Flop (Latch) Reset-to-Q		1.2		1.6		1.8		2.1		2.9	ns
Logic Module Predicted Routing Delays ²												
t _{RD1}	FO = 1 Routing Delay		0.7		0.8		0.9		1.0		1.4	ns
t _{RD2}	FO = 2 Routing Delay		0.9		1.0		1.2		1.4		1.9	ns
t _{RD3}	FO = 3 Routing Delay		1.2		1.3		1.5		1.7		2.4	ns
t _{RD4}	FO = 4 Routing Delay		1.4		1.5		1.7		2.0		2.9	ns
t _{RD8}	FO = 8 Routing Delay		2.3		2.6		2.9		3.4		4.8	ns
Logic Module Sequential Timing ^{3, 4}												
t _{SUD}	Flip-Flop (Latch) Data Input Set-Up	0.3		0.4		0.4		0.5		0.7		ns
t _{HD}	Flip-Flop (Latch) Data Input Hold	0.0		0.0		0.0		0.0		0.0		ns
t _{SUENA}	Flip-Flop (Latch) Enable Set-Up	0.4		0.5		0.5		0.6		0.8		ns
t _{HENA}	Flip-Flop (Latch) Enable Hold	0.0		0.0		0.0		0.0		0.0		ns
t _{WCLKA}	Flip-Flop (Latch) Clock Active Pulse Width	3.4		3.8		4.3		5.0		7.0		ns

Table 38 • A42MX09 Timing Characteristics (Nominal 5.0 V Operation) (continued)(Worst-Case Commercial Conditions, VCCA = 4.75 V, T_J = 70°C)

Parameter / Description		–3 Speed		–2 Speed		–1 Speed		Std Speed		–F Speed		Units
		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
t _{WASYN}	Flip-Flop (Latch) Asynchronous Pulse Width	4.5		4.9		5.6		6.6		9.2		ns
t _A	Flip-Flop Clock Input Period	3.5		3.8		4.3		5.1		7.1		ns
t _{INH}	Input Buffer Latch Hold	0.0		0.0		0.0		0.0		0.0		ns
t _{INSU}	Input Buffer Latch Set-Up	0.3		0.3		0.4		0.4		0.6		ns
t _{OUTH}	Output Buffer Latch Hold	0.0		0.0		0.0		0.0		0.0		ns
t _{OUTSU}	Output Buffer Latch Set-Up	0.3		0.3		0.4		0.4		0.6		ns
f _{MAX}	Flip-Flop (Latch) Clock Frequency		268		244		224		195		117	MHz

Table 39 • A42MX09 Timing Characteristics (Nominal 3.3 V Operation) (continued)(Worst-Case Commercial Conditions, VCCA = 3.0 V, T_J = 70°C)

Parameter / Description			-3 Speed		-2 Speed		-1 Speed		Std Speed		-F Speed		Units
			Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
Input Module Propagation Delays													
t _{INYH}	Pad-to-Y HIGH		1.5		1.6		1.8		2.17		3.0		ns
t _{INYL}	Pad-to-Y LOW		1.2		1.3		1.4		1.7		2.4		ns
t _{INGH}	G to Y HIGH		1.8		2.0		2.3		2.7		3.7		ns
t _{INGL}	G to Y LOW		1.8		2.0		2.3		2.7		3.7		ns
Input Module Predicted Routing Delays ²													
t _{IRD1}	FO = 1 Routing Delay		2.8		3.2		3.6		4.2		5.9		ns
t _{IRD2}	FO = 2 Routing Delay		3.2		3.5		4.0		4.7		6.6		ns
t _{IRD3}	FO = 3 Routing Delay		3.5		3.9		4.4		5.2		7.3		ns
t _{IRD4}	FO = 4 Routing Delay		3.9		4.3		4.9		5.7		8.0		ns
t _{IRD8}	FO = 8 Routing Delay		5.2		5.8		6.6		7.7		10.8		ns
Global Clock Network													
t _{CKH}	Input LOW to HIGH	FO = 32	4.1		4.5		5.1		6.0		8.4		ns
		FO = 256	4.5		5.0		5.6		6.7		9.3		ns
t _{CKL}	Input HIGH to LOW	FO = 32	5.0		5.5		6.2		7.3		10.2		ns
		FO = 256	5.4		6.0		6.8		8.0		11.2		ns
t _{PWH}	Minimum Pulse Width HIGH	FO = 32	1.7		1.9		2.1		2.5		3.5		ns
		FO = 256	1.9		2.1		2.3		2.7		3.8		ns
t _{PWL}	Minimum Pulse Width LOW	FO = 32	1.7		1.9		2.1		2.5		3.5		ns
		FO = 256	1.9		2.1		2.3		2.7		3.8		ns
t _{CKSW}	Maximum Skew	FO = 32	0.4		0.5		0.5		0.6		0.9		ns
		FO = 256	0.4		0.5		0.5		0.6		0.9		ns
t _{SUEXT}	Input Latch External Set-Up	FO = 32	0.0		0.0		0.0		0.0		0.0		ns
		FO = 256	0.0		0.0		0.0		0.0		0.0		ns
t _{HEXT}	Input Latch External Hold	FO = 32	3.3		3.7		4.2		4.9		6.9		ns
		FO = 256	3.7		4.1		4.6		5.5		7.6		ns
t _P	Minimum Period	FO = 32	5.6		6.2		6.7		7.8		12.9		ns
		FO = 256	6.1		6.8		7.4		8.5		14.2		ns
f _{MAX}	Maximum Frequency	FO = 32	177		161		148		129		77		MHz
		FO = 256	161		146		135		117		70		MHz

Table 39 • A42MX09 Timing Characteristics (Nominal 3.3 V Operation) (continued)(Worst-Case Commercial Conditions, VCCA = 3.0 V, T_J = 70°C)

Parameter / Description		–3 Speed		–2 Speed		–1 Speed		Std Speed		–F Speed		Units
		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
TTL Output Module Timing ⁵												
t _{DLH}	Data-to-Pad HIGH		3.4		3.8		4.3		5.1		7.1	ns
t _{DHL}	Data-to-Pad LOW		4.0		4.5		5.1		6.1		8.3	ns
t _{ENZH}	Enable Pad Z to HIGH		3.7		4.1		4.6		5.5		7.6	ns
t _{ENZL}	Enable Pad Z to LOW		4.1		4.5		5.1		6.1		8.5	ns
t _{ENHZ}	Enable Pad HIGH to Z		6.9		7.6		8.6		10.2		14.2	ns
t _{ENLZ}	Enable Pad LOW to Z		7.5		8.3		9.4		11.1		15.5	ns
t _{GLH}	G-to-Pad HIGH		5.8		6.5		7.3		8.6		12.0	ns
t _{GHL}	G-to-Pad LOW		5.8		6.5		7.3		8.6		12.0	ns
t _{LSU}	I/O Latch Set-Up	0.7		0.8		0.9		1.0		1.4		ns
t _{LH}	I/O Latch Hold	0.0		0.0		0.0		0.0		0.0		ns
t _{LCO}	I/O Latch Clock-to-Out (Pad-to-Pad), 64 Clock Loading		8.7		9.7		10.9		12.9		18.0	ns
t _{ACO}	Array Clock-to-Out (Pad-to-Pad),64 Clock Loading		12.2		13.5		15.4		18.1		25.3	ns
d _{TLH}	Capacity Loading, LOW to HIGH	0.00		0.00		0.00		0.10		0.01		ns/pF
d _{THL}	Capacity Loading, HIGH to LOW	0.09		0.10		0.10		0.10		0.10		ns/pF

Table 50 • PQ 100

PQ100				
Pin Number	A40MX02 Function	A40MX04 Function	A42MX09 Function	A42MX16 Function
56	VCC	VCC	I/O	I/O
57	I/O	I/O	GND	GND
58	I/O	I/O	I/O	I/O
59	I/O	I/O	I/O	I/O
60	I/O	I/O	I/O	I/O
61	I/O	I/O	I/O	I/O
62	I/O	I/O	I/O	I/O
63	GND	GND	I/O	I/O
64	I/O	I/O	LP	LP
65	I/O	I/O	VCCA	VCCA
66	I/O	I/O	VCCI	VCCI
67	I/O	I/O	VCCA	VCCA
68	I/O	I/O	I/O	I/O
69	VCC	VCC	I/O	I/O
70	I/O	I/O	I/O	I/O
71	I/O	I/O	I/O	I/O
72	I/O	I/O	GND	GND
73	I/O	I/O	I/O	I/O
74	I/O	I/O	I/O	I/O
75	I/O	I/O	I/O	I/O
76	I/O	I/O	I/O	I/O
77	NC	NC	I/O	I/O
78	NC	NC	I/O	I/O
79	NC	NC	SDI, I/O	SDI, I/O
80	NC	I/O	I/O	I/O
81	NC	I/O	I/O	I/O
82	NC	I/O	I/O	I/O
83	I/O	I/O	I/O	I/O
84	I/O	I/O	GND	GND
85	I/O	I/O	I/O	I/O
86	GND	GND	I/O	I/O
87	GND	GND	PRA, I/O	PRA, I/O
88	I/O	I/O	I/O	I/O
89	I/O	I/O	CLKA, I/O	CLKA, I/O
90	CLK, I/O	CLK, I/O	VCCA	VCCA
91	I/O	I/O	I/O	I/O
92	MODE	MODE	CLKB, I/O	CLKB, I/O

Table 51 • PQ144

PQ144	
Pin Number	A42MX09 Function
43	I/O
44	GNDQ
45	GNDI
46	NC
47	I/O
48	I/O
49	I/O
50	I/O
51	I/O
52	I/O
53	I/O
54	VCC
55	VCCI
56	NC
57	I/O
58	I/O
59	I/O
60	I/O
61	I/O
62	I/O
63	I/O
64	GND
65	GNDI
66	I/O
67	I/O
68	I/O
69	I/O
70	I/O
71	SDO
72	I/O
73	I/O
74	I/O
75	I/O
76	I/O
77	I/O
78	I/O
79	GNDQ

Table 53 • PQ208

PQ208			
Pin Number	A42MX16 Function	A42MX24 Function	A42MX36 Function
21	I/O	I/O	I/O
22	GND	GND	GND
23	I/O	I/O	I/O
24	I/O	I/O	I/O
25	I/O	I/O	I/O
26	I/O	I/O	I/O
27	GND	GND	GND
28	VCCI	VCCI	VCCI
29	VCCA	VCCA	VCCA
30	I/O	I/O	I/O
31	I/O	I/O	I/O
32	VCCA	VCCA	VCCA
33	I/O	I/O	I/O
34	I/O	I/O	I/O
35	I/O	I/O	I/O
36	I/O	I/O	I/O
37	I/O	I/O	I/O
38	I/O	I/O	I/O
39	I/O	I/O	I/O
40	I/O	I/O	I/O
41	NC	I/O	I/O
42	NC	I/O	I/O
43	NC	I/O	I/O
44	I/O	I/O	I/O
45	I/O	I/O	I/O
46	I/O	I/O	I/O
47	I/O	I/O	I/O
48	I/O	I/O	I/O
49	I/O	I/O	I/O
50	NC	I/O	I/O
51	NC	I/O	I/O
52	GND	GND	GND
53	GND	GND	GND
54	I/O	TMS, I/O	TMS, I/O
55	I/O	TDI, I/O	TDI, I/O
56	I/O	I/O	I/O
57	I/O	WD, I/O	WD, I/O

Table 54 • PQ240

PQ240	
Pin Number	A42MX36 Function
15	QCLKC, I/O
16	I/O
17	WD, I/O
18	WD, I/O
19	I/O
20	I/O
21	WD, I/O
22	WD, I/O
23	I/O
24	PRB, I/O
25	I/O
26	CLKB, I/O
27	I/O
28	GND
29	VCCA
30	VCCI
31	I/O
32	CLKA, I/O
33	I/O
34	PRA, I/O
35	I/O
36	I/O
37	WD, I/O
38	WD, I/O
39	I/O
40	I/O
41	I/O
42	I/O
43	I/O
44	I/O
45	QCLKD, I/O
46	I/O
47	WD, I/O
48	WD, I/O
49	I/O
50	I/O
51	I/O

Figure 47 • VQ100

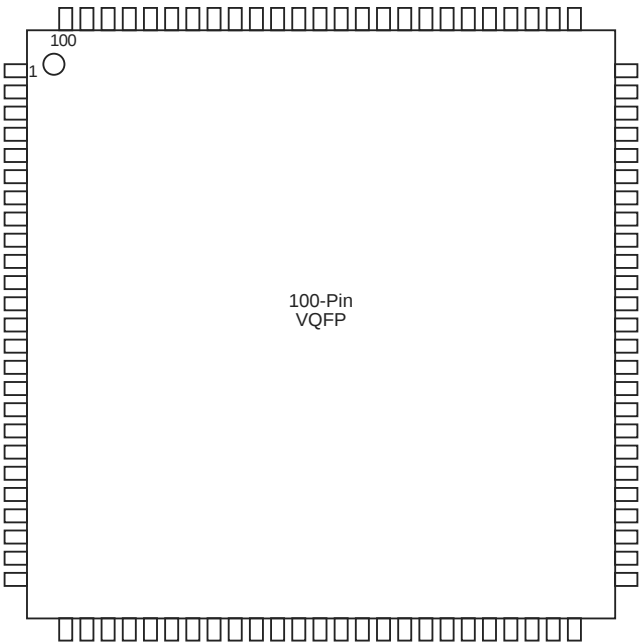


Table 56 • VQ100

VQ100		
Pin Number	A42MX09 Function	A42MX16 Function
1	I/O	I/O
2	MODE	MODE
3	I/O	I/O
4	I/O	I/O
5	I/O	I/O
6	I/O	I/O
7	GND	GND
8	I/O	I/O
9	I/O	I/O
10	I/O	I/O
11	I/O	I/O
12	I/O	I/O
13	I/O	I/O
14	VCCA	NC
15	VCCI	VCCI
16	I/O	I/O
17	I/O	I/O
18	I/O	I/O
19	I/O	I/O
20	GND	GND

Table 57 • TQ176

TQ176			
Pin Number	A42MX09 Function	A42MX16 Function	A42MX24 Function
84	I/O	I/O	WD, I/O
85	I/O	I/O	WD, I/O
86	NC	I/O	I/O
87	SDO, I/O	SDO, I/O	SDO, TDO, I/O
88	I/O	I/O	I/O
89	GND	GND	GND
90	I/O	I/O	I/O
91	I/O	I/O	I/O
92	I/O	I/O	I/O
93	I/O	I/O	I/O
94	I/O	I/O	I/O
95	I/O	I/O	I/O
96	NC	I/O	I/O
97	NC	I/O	I/O
98	I/O	I/O	I/O
99	I/O	I/O	I/O
100	I/O	I/O	I/O
101	NC	NC	I/O
102	I/O	I/O	I/O
103	NC	I/O	I/O
104	I/O	I/O	I/O
105	I/O	I/O	I/O
106	GND	GND	GND
107	NC	I/O	I/O
108	NC	I/O	TCK, I/O
109	LP	LP	LP
110	VCCA	VCCA	VCCA
111	GND	GND	GND
112	VCCI	VCCI	VCCI
113	VCCA	VCCA	VCCA
114	NC	I/O	I/O
115	NC	I/O	I/O
116	NC	VCCA	VCCA
117	I/O	I/O	I/O
118	I/O	I/O	I/O
119	I/O	I/O	I/O
120	I/O	I/O	I/O

Table 60 • BG272

BG272	
Pin Number	A42MX36 Function
J9	GND
J10	GND
J11	GND
J12	GND
J17	VCCA
J18	I/O
J19	I/O
J20	I/O
K1	I/O
K2	I/O
K3	I/O
K4	VCCI
K9	GND
K10	GND
K11	GND
K12	GND
K17	I/O
K18	VCCA
K19	VCCA
K20	LP
L1	I/O
L2	I/O
L3	VCCA
L4	VCCA
L9	GND
L10	GND
L11	GND
L12	GND
L17	VCCI
L18	I/O
L19	I/O
L20	TCK, I/O
M1	I/O
M2	I/O
M3	I/O
M4	VCCI
M9	GND

Table 60 • BG272

BG272	
Pin Number	A42MX36 Function
M10	GND
M11	GND
M12	GND
M17	I/O
M18	I/O
M19	I/O
M20	I/O
N1	I/O
N2	I/O
N3	I/O
N4	VCCI
N17	VCCI
N18	I/O
N19	I/O
N20	I/O
P1	I/O
P2	I/O
P3	I/O
P4	VCCA
P17	I/O
P18	I/O
P19	I/O
P20	I/O
R1	I/O
R2	I/O
R3	I/O
R4	VCCI
R17	VCCI
R18	I/O
R19	I/O
R20	I/O
T1	I/O
T2	I/O
T3	I/O
T4	I/O
T17	VCCA
T18	I/O

Table 62 • CQ172

21	I/O
22	GND
23	VCCI
24	VSV
25	I/O
26	I/O
27	VCC
28	I/O
29	I/O
30	I/O
31	I/O
32	GND
33	I/O
34	I/O
35	I/O
36	I/O
37	GND
38	I/O
39	I/O
40	I/O
41	I/O
42	I/O
43	I/O
44	BININ
45	BINOUT
46	I/O
47	I/O
48	I/O
49	I/O
50	VCCI
51	I/O
52	I/O
53	I/O
54	I/O
55	GND
56	I/O
57	I/O
58	I/O
59	I/O